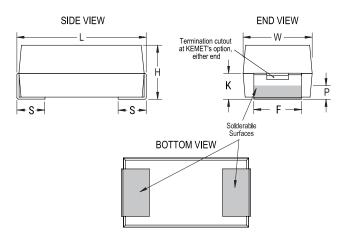


## T497X156K035AH6110

T497 HRA, Tantalum, MnO2 Tantalum, HRA, 15 uF, 10%, 35 VDC, SMD, MnO2, Molded, High Reliability, Medical, N/A, 900 mOhms, 6954, 3.12 mm, 119 mm



Click	here	for	the	3D	model
CIICK	חבו כ	101	uic	JU	HIOUE

General Information	
Series	T497 HRA
Dielectric	MnO2 Tantalum
Style	SMD Chip
Description	SMD, MnO2, Molded, High Reliability, Medical
Features	High Reliability, Medical
RoHS	No
Prop 65	WARNING: Cancer and reproductive harm - https://www.p65warnings.ca.gov /
SCIP Number	1dd2e1b8-26dd-4d52-927c-6f9 d519011aa
Termination	Tin Lead (SnPb)
Qualifications	CWR09/19/29 Style
AEC-Q200	No
Typical Component Weight	590.44 mg
Notes	Note: When solder coated terminations are required, add an additional 0.38mm (0.015inch) to the tolerances for "L", "W", "H", "K", "F" and "S".
MSL	1

Dimensions	
L	6.93mm +/-0.38mm
W	5.41mm +/-0.38mm
Н	2.74mm +/-0.38mm
S	1.19mm +0.25/-0.13mm
F	3.05mm +/-0.13mm
K	1.22mm MIN
Р	0.61mm MIN

Packaging Specifications	
Packaging	T&R, 178mm
Packaging Quantity	500

Specifications	
Capacitance	15 uF
Tolerance	10%
Voltage DC	35 VDC (85C), 23.45 VDC (125C)
Temperature Range	-55/+125°C
Rated Temperature	85°C
Humidity	85C, 85% RH, 1000 Hours, No Load
Dissipation Factor	6% 120Hz 25C
Failure Rate	N/A
ESR	0.9 Ohms (100kHz 25C)
Ripple Current	428 mA (rms, 100kHz 25C)
Leakage Current	5.3 uA (5min 25°C)
Testing and Reliability	Standard Testing Only

Statements of suitability for certain applications are based on our knowledge of typical operating conditions for such applications, but are not intended to constitute - and we specifically disclaim - any warranty concerning suitability for a specific customer application or use. This Information is intended for use only by customers who have the requisite experience and capability to determine the correct products for their application. Any technical advice inferred from this Information or otherwise provided by us with reference to the use of our products is given gratis, and we assume no obligation or liability for the advice given or results obtained.

Generated 05/03/2025 © 2006 - 2025 YAGEO